Designer's™ Data Sheet

TMOS E-FET ™ High Energy Power FET

N-Channel Enhancement-Mode Silicon Gate

This advanced high voltage TMOS E-FET is designed to withstand high energy in the avalanche mode and switch efficiently. This new high energy device also offers a drain-to-source diode with fast recovery time. Designed for high voltage, high speed switching applications such as power supplies, PWM motor controls and other inductive loads, the avalanche energy capability is specified to eliminate the guesswork in designs where inductive loads are switched and offer additional safety margin against unexpected voltage transients.

- Avalanche Energy Capability Specified at Elevated Temperature
- Low Stored Gate Charge for Efficient Switching
- Internal Source-to-Drain Diode Designed to Replace External Zener Transient Suppressor — Absorbs High Energy in the Avalanche Mode
- Source-to-Drain Diode Recovery Time Comparable to Discrete Fast Recovery Diode



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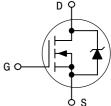
TMOS POWER FET 5.0 AMPERES, 400 VOLTS

 $R_{DS(on)} = 1.0 \Omega$



TO-220AB CASE 221A-06 Style 5





Designer's Data for "Worst Case" Conditions — The Designer's Data Sheet permits the design of most circuits entirely from the information presented. SOA Limit curves — representing boundaries on device characteristics — are given to facilitate "worst case" design.

Preferred devices are Motorola recommended choices for future use and best overall value.

MAXIMUM RATINGS ($T_C = 25^{\circ}C$ unless otherwise noted)

Rating	Symbol	Value	Unit
Drain-Source Voltage	V _{DSS}	400	Vdc
Drain-Gate Voltage (R _{GS} = 1.0 MΩ)	V_{DGR}	400	Vdc
Gate-Source Voltage — Continuous — Non-repetitive	V _{GS} V _{GSM}	±20 ±40	Vdc Vpk
Drain Current — Continuous — Pulsed	I _D I _{DM}	5.0 12	Adc
Total Power Dissipation @ T _C = 25°C Derate above 25°C	P_{D}	75 0.6	Watts W/°C
Operating and Storage Temperature Range	T _J , T _{stg}	-55 to 150	°C

UNCLAMPED DRAIN-TO-SOURCE AVALANCHE CHARACTERISTICS (T_J < 150°C)

Single Pulse Drain-to-Source Avalanche Energy — T _J = 25°C	W _{DSR} (1)	290	mJ
— T _J = 100°C		46	
Repetitive Pulse Drain-to-Source Avalanche Energy	W _{DSR} (2)	7.4	

THERMAL CHARACTERISTICS

Thermal Resistance — Junction to Case — Junction to Ambient	R _{θJC} R _{θJA}	1.67 62.5	°C/W
Maximum Lead Temperature for Soldering Purposes, 1/8" from case for 10 seconds	TL	260	°C

 $⁽¹⁾ V_{DD} = 50 V, I_D = 5.0 A$

⁽²⁾ Pulse Width and frequency is limited by T_J(max) and thermal response

ELECTRICAL CHARACTERISTICS (T_J = 25°C unless otherwise noted)

Cha	racteristic	Symbol	Min	Тур	Max	Unit
FF CHARACTERISTICS						
Drain-to-Source Breakdown Voltage (V_{GS} = 0, I_D = 250 μ Adc)	е	V _{(BR)DSS}	400	_	_	Vdc
Zero Gate Voltage Drain Current $(V_{DS} = 400 \text{ V}, V_{GS} = 0)$ $(V_{DS} = 320 \text{ V}, V_{GS} = 0, T_{J} = 125^{\circ}$	C)	I _{DSS}	<u> </u>	<u> </u>	0.25 1.0	mAdc
Gate-Body Leakage Current, Forward (V _{GSF} = 20 Vdc, V _{DS} = 0)		I _{GSSF}	_	_	100	nAdc
Gate-Body Leakage Current, Reve	erse (V _{GSR} = 20 Vdc, V _{DS} = 0)	I _{GSSR}	_	_	100	nAdc
N CHARACTERISTICS*						
Gate Threshold Voltage $(V_{DS} = V_{GS}, I_D = 250 \mu Adc)$ $(T_J = 125^{\circ}C)$		V _{GS(th)}	2.0 1.5	<u> </u>	4.0 3.5	Vdc
Static Drain-Source On-Resistance	e (V _{GS} = 10 Vdc, I _D = 2.5 Adc)	R _{DS(on)}	_	0.8	1.0	Ohm
Drain-Source On-Voltage ($V_{GS} = 1$ ($I_D = 5.0 \text{ A}$) ($I_D = 2.5 \text{ A}, T_J = 100^{\circ}\text{C}$)	0 Vdc)	V _{DS(on)}	_ _	Z ^C	6.2 5.0	Vdc
Forward Transconductance (V _{DS} =	15 Vdc, I _D = 2.5 Adc)	g _{FS}	2.0	<u>/ / / / / / / / / / / / / / / / / / / </u>	_	mhos
YNAMIC CHARACTERISTICS						•
Input Capacitance		C _{iss}	9	775	_	pF
Output Capacitance	$(V_{DS} = 25 \text{ V}, V_{GS} = 0,$ f = 1.0 MHz)	C _{oss}	01	96	=	
Transfer Capacitance		C _{rss}		22	=	
WITCHING CHARACTERISTICS*		9 6	O,			
Turn-On Delay Time	5	t _{d(on)}	_	24	_	ns
Rise Time	$(V_{DD} = 250 \text{ V}, I_D \approx 5.0 \text{ A},$ $R_G = 12 \Omega, R_L = 50 \Omega,$	ţr	_	34	_	
Turn-Off Delay Time	$V_{GS(on)} = 10 \text{ V}$	t _{d(off)}	_	60	_	
Fall Time		t _f	_	36	_	
Total Gate Charge		Q _g	_	27	32	nC
Gate-Source Charge	$(V_{DS} = 320 \text{ V}, I_D = 5.0 \text{ A}, V_{GS} = 10 \text{ V})$	Q_{gs}	_	3.5	_	
Gate-Drain Charge	AHISARAR	Q_{gd}	_	14	_	
OURCE-DRAIN DIODE CHARACT	ERISTICS*					
Forward On-Voltage	co.ek.	V _{SD}	_	_	1.4	Vdc
Forward Turn-On Time	$(I_S = 5.0 \text{ A, di/dt} = 100 \text{ A/}\mu\text{s})$	t _{on}		**		ns
Reverse Recovery Time	SYOK	t _{rr}	_		660	
ITERNAL PACKAGE INDUCTANC						
Internal Drain Inductance (Measured from the contact screv (Measured from the drain lead 0.2	v on tab to center of die) 25" from package to center of die)	L _d	_ _	3.5 4.5	_	nH
Internal Source Inductance	0.25" from package to source bond pad)	L _s	_	7.5	_	

^{*}Indicates Pulse Test: Pulse Width = 300 μ s Max, Duty Cycle \leq 2.0%.

TYPICAL ELECTRICAL CHARACTERISTICS

^{**} Limited by circuit inductance.

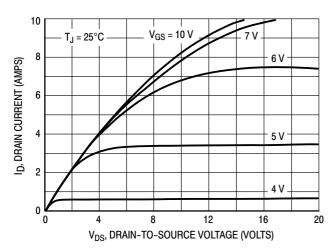


Figure 1. On-Region Characteristics

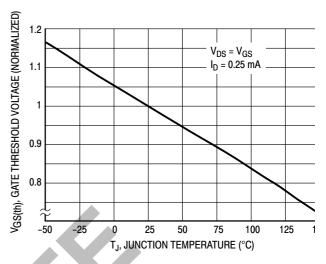


Figure 2. Gate-Threshold Voltage Variation
With Temperature

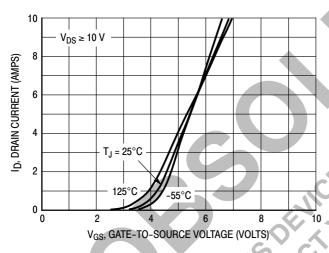


Figure 3. Transfer Characteristics

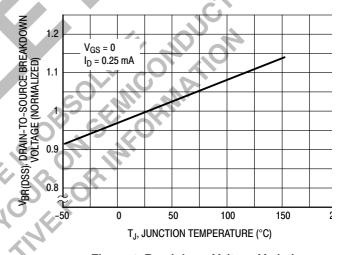


Figure 4. Breakdown Voltage Variation With Temperature

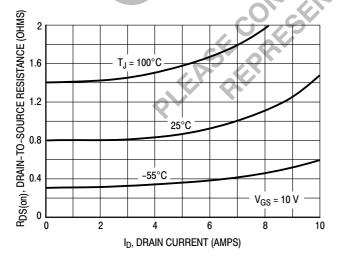


Figure 5. On-Resistance versus Drain Current

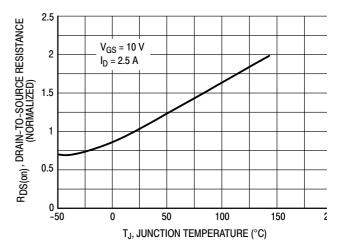


Figure 6. On-Resistance Variation
With Temperature

SAFE OPERATING AREA INFORMATION

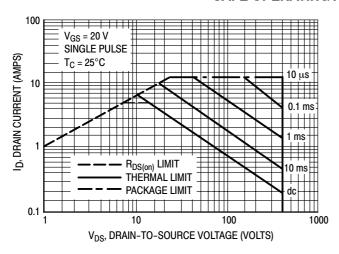


Figure 7. Maximum Rated Forward Biased Safe Operating Area



The FBSOA curves define the maximum drain-to-source voltage and drain current that a device can safely handle when it is forward biased, or when it is on, or being turned on. Because these curves include the limitations of simultaneous high voltage and high current, up to the rating of the device, they are especially useful to designers of linear systems. The curves are based on a case temperature of 25°C and a maximum junction temperature of 150°C. Limitations for repetitive pulses at various case temperatures can be determined by using the thermal response curves. Motorola Application Note, AN569, "Transient Thermal Resistance-General Data and Its Use" provides detailed instructions.

SWITCHING SAFE OPERATING AREA

The switching safe operating area (SOA) of Figure 8 is the boundary that the load line may traverse without incurring damage to the MOSFET. The fundamental limits are the peak current, I_{DM} and the breakdown voltage, $V_{(BR)DSS}$. The switching SOA shown in Figure 8 is

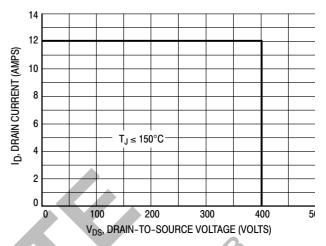


Figure 8. Maximum Rated Switching Safe Operating Area

applicable for both turn-on and turn-off of the devices for switching times less than one microsecond.

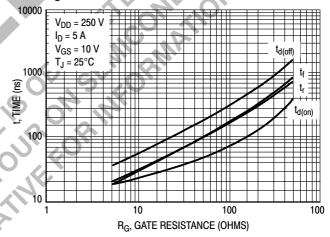
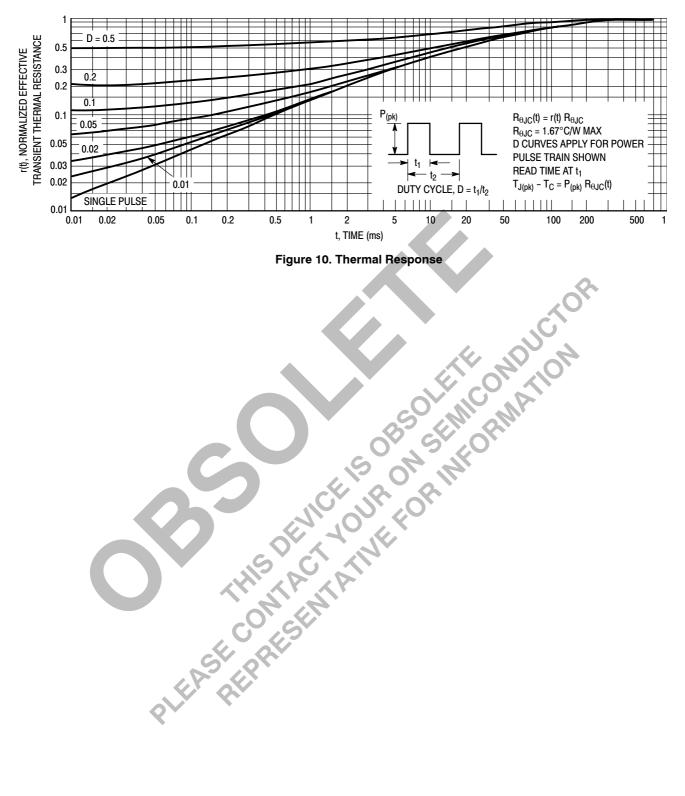
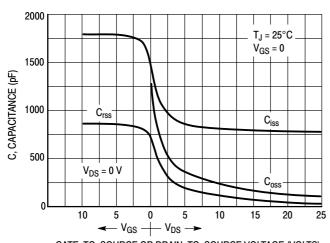


Figure 9. Resistive Switching Time Variation versus Gate Resistance





GATE-TO-SOURCE OR DRAIN-TO-SOURCE VOLTAGE (VOLTS)

Figure 11. Capacitance Variation

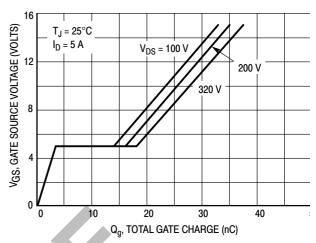


Figure 12. Gate Charge versus Gate-To-Source Voltage

COMMUTATING SAFE OPERATING AREA (CSOA)

The Commutating Safe Operating Area (CSOA) of Figure 14 defines the limits of safe operation for commutated source–drain current versus re–applied drain voltage when the source–drain diode has undergone forward bias. The curve shows the limitations of I_{FM} and peak V_{DS} for a given rate of change of source current. It is applicable when waveforms similar to those of Figure 11 are present. Full or half–bridge PWM DC motor controllers are common applications requiring CSOA data.

Device stresses increase with increasing rate of change of source current so dl_s/dt is specified with a maximum value. Higher values of dl_s/dt require an appropriate derating of l_{FM} , peak V_{DS} or both. Ultimately dl_s/dt is limited primarily by device, package, and circuit impedances. Maximum device stress occurs during t_{rr} as the diode goes from conduction to reverse blocking.

 $V_{DS(pk)}$ is the peak drain-to-source voltage that the device must sustain during commutation; I_{FM} is the maximum forward source-drain diode current just prior to the onset of commutation.

 V_R is specified at 80% of $V_{(BR)DSS}$ to ensure that the CSOA stress is maximized as I_S decays from I_{RM} to zero.

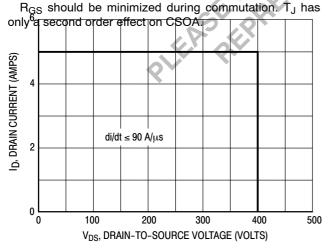


Figure 13. Commutating Safe Operating Area (CSOA)

Stray inductances in Motorola's test circuit are assumed to be practical minimums. dV_{DS}/dt in excess of 10 V/ns was attaimed with dls/dt of 400 A/tts.

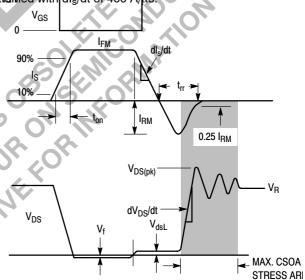


Figure 15. Commutating Waveforms

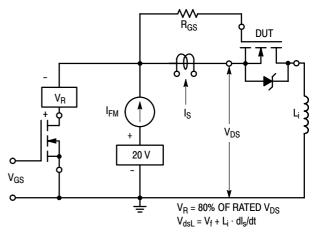


Figure 14. Commutating Safe Operating Area Test Circuit

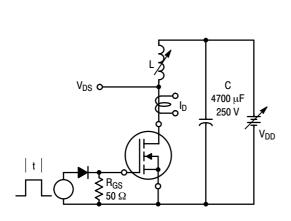


Figure 16. Unclamped Inductive Switching Test Circuit

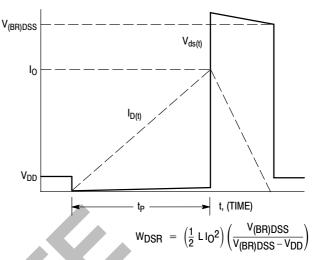
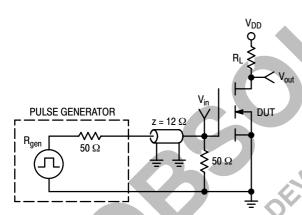


Figure 17. Unclamped Inductive Switching Waveforms

RESISTIVE SWITCHING



*Note: The Mirror is shorted to the Kelvin terminal for this test

Figure 18. Switching Test Circuit

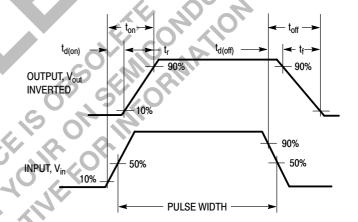
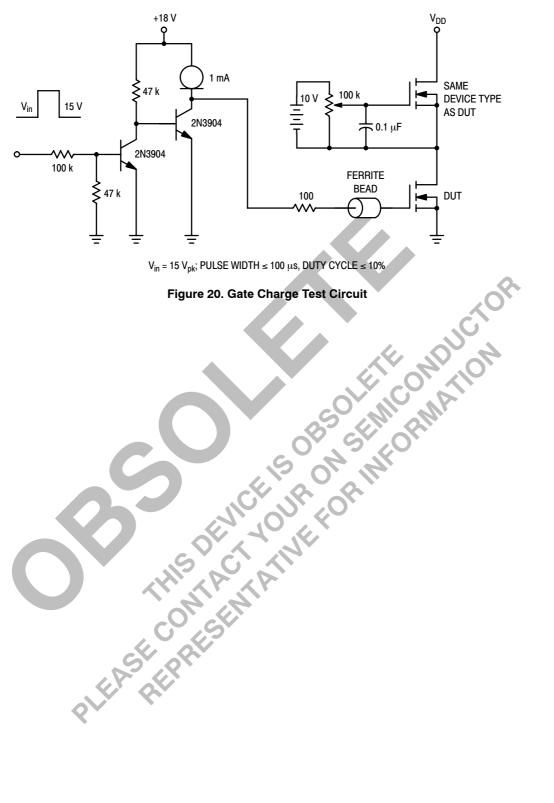
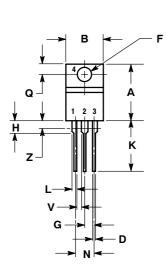


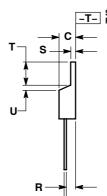
Figure 19. Switching Waveforms



PACKAGE DIMENSIONS

CASE 221A-06 ISSUE Y





-T- SEATING STYLE 5: PIN 1. GATE

NOTES:

- DIMENSIONING AND TOLERANCING PER ANSI Y14.5M, 1982.
- CONTROLLING DIMENSION: INCH.
 DIMENSION Z DEFINES A ZONE WHERE ALL **BODY AND LEAD IRREGULARITIES ARE** ALLOWED.

							
↑ ↑				INC	HES	MILLIN	IFTED
			DIM	MIN			
A ===					MAX	MIN	MAX
↑			A	0.570	0.620	14.48	15.7
↓ υ_	STYLE 5:		В	0.380	0.405	9.66	10.20
<u> </u>	PIN 1.		C	0.160	0.190	4.07	4.8
 	2.	DRAIN	D	0.025	0.035	0.64	0.8
	3.	SOURCE	F	0.142	0.147	3.61	3.73
	4.	DRAIN	G	0.095	0.105	2.42	2.6
			H	0.110	0.155	2.80	3.9
			J	0.018	0.025	0.46	0.6
H I			K	0.500	0.562	12.70	14.2
n . ₄			L	0.045	0.060	1.15	1.5
R → ←			N	0.190	0.210	4.83	5.3
			Q	0.100	0.120	2.54	3.0
J—> -			R	0.080	0.110	2.04	2.79
			S	0.045	0.055	1.15	1.39
			T	0.235	0.255	5.97	6.4
			U	0.000	0.050	0.00	1.2
			V	0.045	7.7	1.15	
			Z		0.080	4	2.04
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